

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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Examiner		Art Unit		Page 1 of 1
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*	B	US-2003/0126240	07-2003	Vosseler, Frank	709/221
*	C	US-6,594,684	07-2003	Hodjat et al.	709/202
*	D	US-7,086,086	08-2006	Ellis, Alonzo	726/15
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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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